Sawn bumped 120µm wafer addendum Rev. 3.0 — 18 July 2007

141130

**Product data sheet PUBLIC** 

#### **General description** 1.

The MF1 IC S20 05 is a contactless Smart Card IC designed for card IC coils following the "Mifare card IC coil design guide" and is qualified to work properly in NXP' reader environment, which is built according to NXP' specification.

This specification describes electrical, physical and dimensional properties of wafers.

### 2. Ordering information

Table 1.	Ordering information			
Type number		Package		
		Name	Description	Ordering Code
MF1ICS2	005W/U7D		Die on sawn wafer	9352 851 56005

## 3. Mechanical specification

3.1	Wafer	
	• Diameter:	8"
	Thickness:	120 $\mu$ m $\pm$ 15 $\mu$ m
	<ul> <li>Flatness:</li> </ul>	not applicable
	• PGDW:	24892
3.2	Wafer backside	
	Material:	Si
	• Treatment:	ground and stress relieve
3.3	Chip dimensions	
	Chip size:	1.11 x 1.06 mm
	Scribe lines:	x-line: 80 μm
		y-line: 80 µm
3.4	Passivation	

•	Туре:	sandwich structure
•	Material:	PSG / Nitride



3.5

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Thickness:	500 nm / 600 nm
Au bump	
Bump material:	> 99.9% pure Au
<ul> <li>Bump hardness:</li> </ul>	35 – 80 HV 0.005
<ul> <li>Bump shear strength:</li> </ul>	> 70 MPa
Bump height:	18 μm
<ul> <li>Bump height uniformity:</li> </ul>	
<ul> <li>within a die:</li> </ul>	± 2 μm
<ul> <li>within a wafer:</li> </ul>	± 3 μm
<ul> <li>wafer to wafer:</li> </ul>	± 4 μm
<ul> <li>Bump flatness:</li> </ul>	± 1.5 μm
Bump size:	
– LA, LB, VSS <sup>1</sup>	104 x 104 μm
– TESTIO <sup>1</sup>	89 x 104 μm
<ul> <li>Bump size variation:</li> </ul>	± 5 μm
Under bump metallization:	sputtered TiW

Remark: Substrate is connected to VSS.

#### 3.6 Fail die identification

Electronic wafer mapping covers the electrical test results and additionally the results of mechanical/ visual inspection.

No inkdots are applied.

<sup>1.</sup>Pads VSS and TESTIO are disconnected when wafer is sawn.

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### 4. Limiting values

#### Table 2. Limiting values<sup>[1][2][3]</sup>

In accordance with the Absolute Maximum Rating System (IEC 134)

Symbol	Parameter		Min	Max	Unit
I <sub>IN</sub>	Input Current		-	30	mA
P <sub>TOT</sub>	Total power dissipation per package		-	200	mW
T <sub>STOR</sub>	Storage temperature		-55	125	°C
T <sub>OP</sub>	Operating temperature		-25	70	°C
V <sub>ESD</sub>	Electrostatic discharge voltage	[4]	2	-	kV
I <sub>LU</sub>	Latch-up current		$\pm100$		mA

[1] Stresses above one or more of the limiting values may cause permanent damage to the device

[2] These are stress ratings only. Operation of the device at these or any other conditions above those given in the Characteristics section of the specification is not implied

[3] Exposure to limiting values for extended periods may affect device reliability

[4] MIL Standard 883-C method 3015; Human body model: C = 100 pF, R = 1.5 kW

### 5. Characteristics

Table 3.	Electrical characteristics [1][2][3]					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
f <sub>IN</sub>	Input frequency		-	13.56	-	MHz
C <sub>IN</sub>	Input capacitance (LCR meter HP4258)	22 °C, Cp-D, 13.56 MHz, 2 V	14.4	16.1	17.4	pF
t <sub>W</sub>	EEPROM write time		-	2.9	-	ms
t <sub>RET</sub>	EEPROM data retention		10			years
$N_{WE}$	EEPROM write endurance		10 <sup>5</sup>			cycles

[1] Stresses above one or more of the limiting values may cause permanent damage to the device

[2] These are stress ratings only. Operation of the device at these or any other conditions above those given in the Characteristics section of the specification is not implied

[3] Exposure to limiting values for extended periods may affect device reliability

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## 6. Chip orientation and bond pad locations



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### 7. References

- Data sheet "General wafer specification for 8" wafers"
- Data sheet "Standard card IC MF1 IC S50 memory contents after test"
- Data sheet "Standard card IC MF1 IC S50 functional Specification"
- Product qualification package "Standard card IC MF1 IC S50 05"
- Application note "Mifare, card IC coil design guide"

### 8. Revision history

Table 4. Re	vision history			
Document ID	Release date	Data sheet status	Change notice	Supersedes
141130	July 2007	Product data sheet		
Modifications:	<ul> <li>The format of this of Semiconductors.</li> </ul>	lata sheet has been redesigned to comp	bly with the new identity	guidelines of NXP
	<ul> <li>Legal texts have be</li> </ul>	een adapted to the new company name.		

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### 9. Legal information

#### 9.1 Data sheet status

Document status[1][2]	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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Table 3. Table 4.

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